

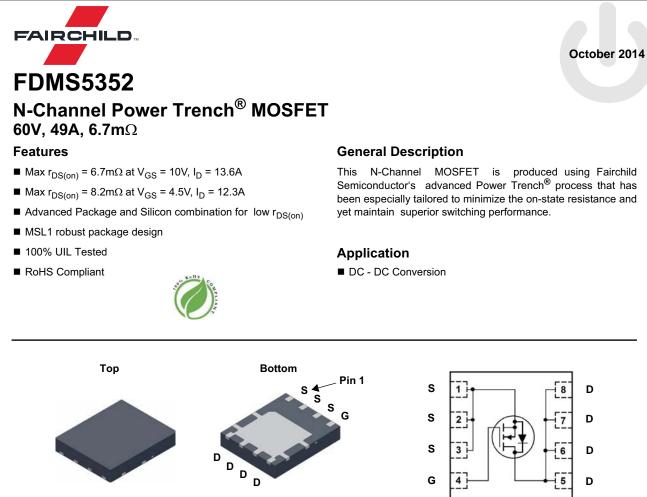
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Power 56



Symbol	Parameter			Ratings	Units	
V _{DS}	Drain to Source Voltage			60	V	
V _{GS}	Gate to Source Voltage			±20	V	
I _D	Drain Current -Continuous (Package limited)	T _C = 25°C		49		
	-Continuous (Silicon limited)	T _C = 25°C		88	_	
	-Continuous	T _A = 25°C	(Note 1a)	13.6	- A	
	-Pulsed		100			
E _{AS}	Single Pulse Avalanche Energy		(Note 3)	600	mJ	
P _D	Power Dissipation	T _C = 25°C		104	w	
	Power Dissipation	T _A = 25°C	(Note 1a)	2.5		
T _J , T _{STG}	Operating and Storage Junction Temperature Range			-55 to +150	°C	

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case	1.2	°C/W
R_{\thetaJA}	Thermal Resistance, Junction to Ambient (Note	e 1a) 50	0/10

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS5352	FDMS5352	Power 56	13"	12mm	3000 units

Source Breakdown Voltage wn Voltage Temperature nt e Voltage Temperature source Leakage Current Source Threshold Voltage Source Threshold Voltage ture Coefficient ain to Source On Resistance Transconductance eristics bacitance	$\begin{split} I_{D} &= 250 \mu A, V_{GS} = 0 \\ I_{D} &= 250 \mu A, reference \\ V_{GS} &= 0V, V_{DS} = 48' \\ V_{GS} &= \pm 20V, V_{DS} = 48' \\ V_{GS} &= \pm 20V, V_{DS} = 0 \\ \hline \\ V_{GS} &= 10V, I_{D} = 250 \\ I_{D} &= 250 \mu A, reference \\ V_{GS} &= 10V, I_{D} = 13. \\ V_{GS} &= 4.5V, I_{D} = 13. \\ V_{DD} &= 5V, I_{D} = 13.6 \\ \end{split}$	ced to 25°C V, DV DµA ced to 25°C 6A .3A 6A, TJ = 125°C	60	57 57 1.8 -6.6 5.6 6.7	1 ±100 3.0 6.7	V mV/°C μA nA V mV/°C
Source Breakdown Voltage wn Voltage Temperature nt e Voltage Drain Current Source Leakage Current S Source Threshold Voltage Source Threshold Voltage ture Coefficient ain to Source On Resistance Transconductance eristics	$\begin{split} & I_{D} = 250 \mu \text{A}, \text{ reference} \\ & V_{GS} = 0\text{V}, V_{DS} = 48^{\circ} \\ & V_{GS} = \pm 20\text{V}, V_{DS} = 48^{\circ} \\ & V_{GS} = \pm 20\text{V}, V_{DS} = 10^{\circ} \\ & I_{D} = 250 \mu \text{A}, \text{ reference} \\ & I_{D} = 250 \mu \text{A}, \text{ reference} \\ & V_{GS} = 10\text{V}, I_{D} = 13. \\ & V_{GS} = 4.5\text{V}, I_{D} = 12. \\ & V_{GS} = 10\text{V}, I_{D} = 13.6 \\ \hline \end{aligned}$	ced to 25°C V, DV DµA ced to 25°C 6A .3A 6A, TJ = 125°C		1.8 -6.6 5.6	±100	mV/°C μA nA
wn Voltage Temperature nt e Voltage Drain Current Source Leakage Current S Source Threshold Voltage Source Threshold Voltage ture Coefficient ain to Source On Resistance Transconductance eristics	$\begin{split} & I_{D} = 250 \mu \text{A}, \text{ reference} \\ & V_{GS} = 0\text{V}, V_{DS} = 48^{\circ} \\ & V_{GS} = \pm 20\text{V}, V_{DS} = 48^{\circ} \\ & V_{GS} = \pm 20\text{V}, V_{DS} = 10^{\circ} \\ & I_{D} = 250 \mu \text{A}, \text{ reference} \\ & I_{D} = 250 \mu \text{A}, \text{ reference} \\ & V_{GS} = 10\text{V}, I_{D} = 13. \\ & V_{GS} = 4.5\text{V}, I_{D} = 12. \\ & V_{GS} = 10\text{V}, I_{D} = 13.6 \\ \hline \end{aligned}$	ced to 25°C V, DV DµA ced to 25°C 6A .3A 6A, TJ = 125°C	1.0	1.8 -6.6 5.6	±100	μA nA V
Source Leakage Current Source Threshold Voltage Source Threshold Voltage ture Coefficient ain to Source On Resistance Transconductance eristics	$V_{GS} = \pm 20V, V_{DS} = 10$ $V_{GS} = V_{DS}, I_D = 250$ $I_D = 250\mu A, reference$ $V_{GS} = 10V, I_D = 13.$ $V_{GS} = 4.5V, I_D = 12.$ $V_{GS} = 10V, I_D = 13.6$	0V DμA ced to 25°C 6A .3A 6A, T _J = 125°C	1.0	-6.6 5.6	±100	nA V
s Source Threshold Voltage Source Threshold Voltage ture Coefficient ain to Source On Resistance Transconductance eristics	$V_{GS} = V_{DS}, I_D = 250$ $I_D = 250 \mu A, referenceV_{GS} = 10V, I_D = 13.$ $V_{GS} = 4.5V, I_D = 12$ $V_{GS} = 10V, I_D = 13.0$	DμA ced to 25°C 6A .3A 6A, TJ = 125°C	1.0	-6.6 5.6	3.0	V
Source Threshold Voltage Source Threshold Voltage ture Coefficient ain to Source On Resistance Transconductance eristics	$\begin{split} I_{D} &= 250 \mu \text{A}, \text{ reference} \\ V_{GS} &= 10 \text{V}, \ I_{D} &= 13. \\ V_{GS} &= 4.5 \text{V}, \ I_{D} &= 12. \\ V_{GS} &= 10 \text{V}, \ I_{D} &= 13.6 \\ \end{split}$	ced to 25°C 6A .3A 6A, T _J = 125°C	1.0	-6.6 5.6		
Source Threshold Voltage Source Threshold Voltage ture Coefficient ain to Source On Resistance Transconductance eristics	$\begin{split} I_{D} &= 250 \mu \text{A}, \text{ reference} \\ V_{GS} &= 10 \text{V}, \ I_{D} &= 13. \\ V_{GS} &= 4.5 \text{V}, \ I_{D} &= 12. \\ V_{GS} &= 10 \text{V}, \ I_{D} &= 13.6 \\ \end{split}$	ced to 25°C 6A .3A 6A, T _J = 125°C	1.0	-6.6 5.6		
Source Threshold Voltage ture Coefficient ain to Source On Resistance Transconductance eristics	$\begin{split} I_{D} &= 250 \mu \text{A}, \text{ reference} \\ V_{GS} &= 10 \text{V}, \ I_{D} &= 13. \\ V_{GS} &= 4.5 \text{V}, \ I_{D} &= 12. \\ V_{GS} &= 10 \text{V}, \ I_{D} &= 13.6 \\ \end{split}$	ced to 25°C 6A .3A 6A, T _J = 125°C		-6.6 5.6		
ture Coefficient ain to Source On Resistance Transconductance eristics	$V_{GS} = 10V, I_D = 13.$ $V_{GS} = 4.5V, I_D = 12$ $V_{GS} = 10V, I_D = 13.6$	6A .3A 6A, T _J = 125°C		5.6	6.7	mV/°C
Transconductance eristics	$V_{GS} = 4.5V, I_D = 12$ $V_{GS} = 10V, I_D = 13.6$.3A 6A, T _J = 125°C			6.7	
Transconductance eristics	V _{GS} = 10V, I _D = 13.6	6A, T _J = 125°C		67		
eristics				0.1	8.2	mΩ
eristics	$V_{DD} = 5V, I_D = 13.6$	Δ		9.7	11.6	
				76		S
				5220	6940	pF
apacitance	$-V_{DS} = 30V, V_{GS} = 0$	V,		410	545	pF
Transfer Capacitance	f = 1MHz			225	335	pF
sistance	f = 1MHz		0.1	1.3	2.6	Ω
e	$V_{DD} = 30V, I_D = 13.6A,$ $V_{CS} = 10V, R_{CEN} = 6\Omega$			19 11 58	34 21 93	ns ns ns
•		+				ns
	V _{CS} =0Vto10V					nC
•		/pp = 30V				nC
•						nC
	-	-		17		nC
do Charactoristics				LI		1
	$V_{CC} = 0V_{LC} = 13.64$	(Note 2)		0.8	1.3	
Drain Diode Forward Voltage	$V_{GS} = 0V, I_S = 2.1A$	(Note 2)		0.7	1.2	V
Recovery Time	$I_{\rm F} = 13.6$ A, di/dt = 10			39	63	ns
	cteristics Delay Time	Delay Time VDD 30V, ID 13.6 Delay Time VGS 10V, RGEN 100, RGEN	Delay Time $V_{DD} = 30V, I_D = 13.6A,$ Delay Time $V_{GS} = 10V, R_{GEN} = 6\Omega$ Delay Time $V_{GS} = 10V, R_{GEN} = 6\Omega$ Delay Time $V_{GS} = 0V to 10V$ Delay Time $V_{GS} = 0V to 5V$ Delay Time $V_{DD} = 30V,$ Delay Time $V_{DD} = 30V,$ Delay Time $V_{DD} = 13.6A$ Drain "Miller" Charge $V_{DD} = 13.6A$ Drain "Diode, Forward Voltage $V_{GS} = 0V, I_S = 13.6A$	Delay Time VDD = 30V, ID = 13.6A, Delay Time VGS = 10V, RGEN = 60 Delay Time VGS = 0V to 10V Delay Time VGS = 0V to 5V Delay Time VGS = 0V, IS = 13.6A Delay Time VGS = 0V, IS = 13.6A Delay Time VGS = 0V, IS = 13.6A	Delay Time19ne $V_{DD} = 30V, I_D = 13.6A, V_{GS} = 10V, R_{GEN} = 6\Omega$ 11Delay Time $V_{GS} = 10V, R_{GEN} = 6\Omega$ 58e $V_{GS} = 0Vto 10V$ 93te Charge $V_{GS} = 0V to 5V$ $V_{DD} = 30V, I_D = 30V, I_D = 13.6A$ Source Charge $V_{GS} = 0V to 5V$ $V_{DD} = 30V, I_D = 13.6A$ Drain "Miller" Charge17de CharacteristicsV_{GS} = 0V, I_S = 13.6A(Note 2)0.8	$ \begin{array}{c c c c c c c c c c c c c c c c c c c $

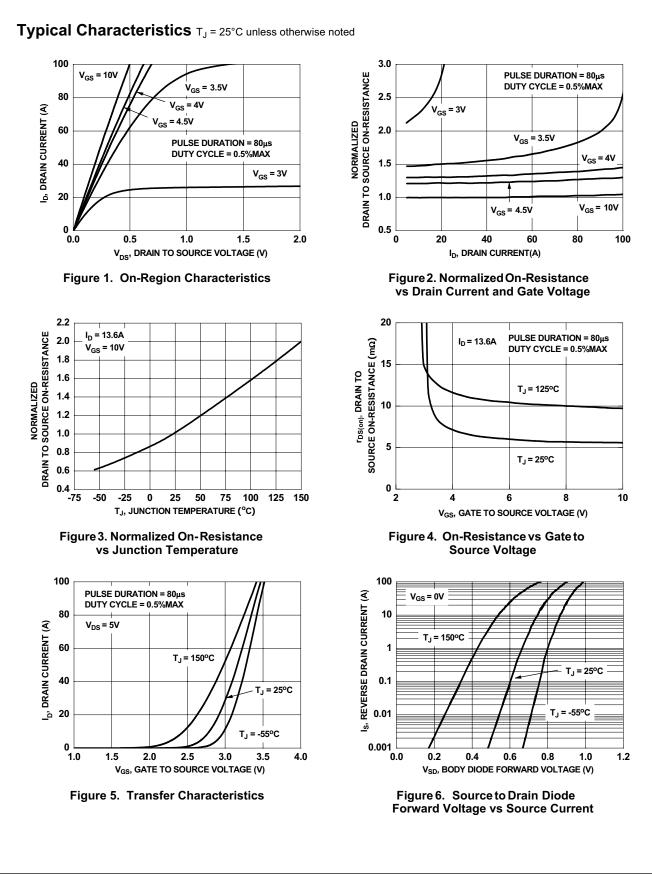
2. Pulse Test: Pulse Width < 300μ s, Duty cycle < 2.0%.

3. Starting T_J = 25°C, L = 3mH, I_{AS} = 20A, V_{DD} = 60V, V_{GS} = 10V

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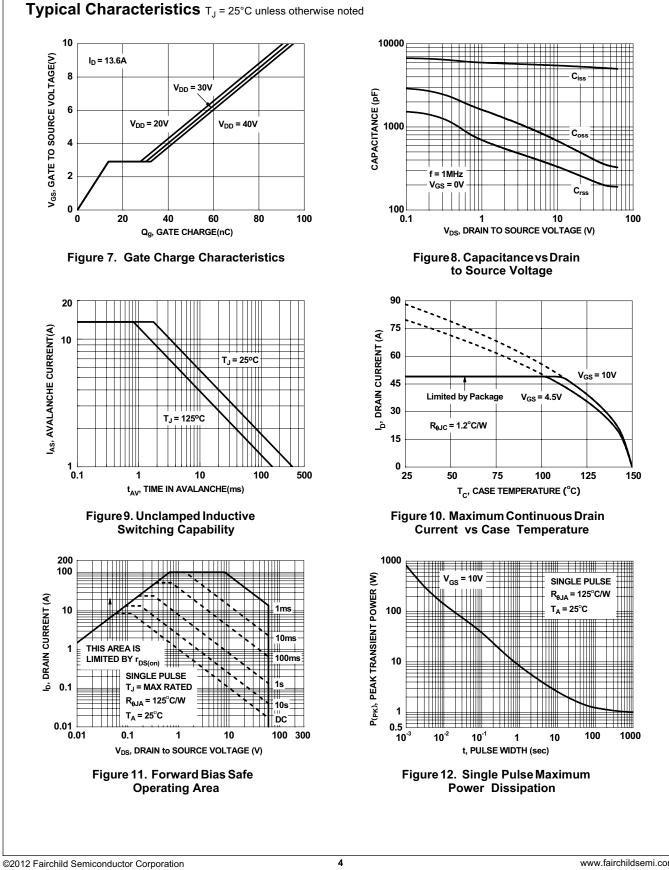
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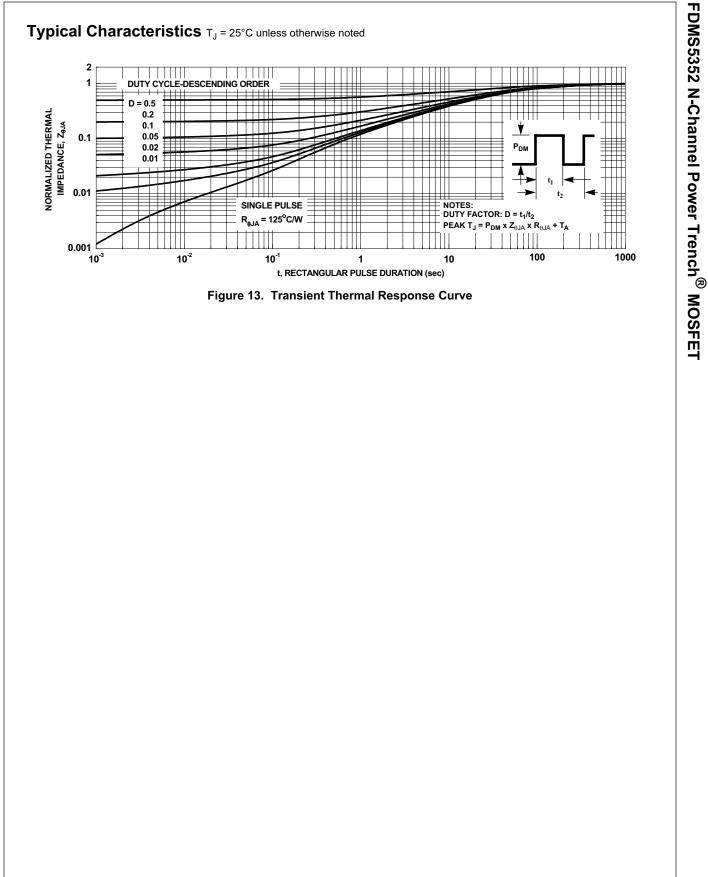
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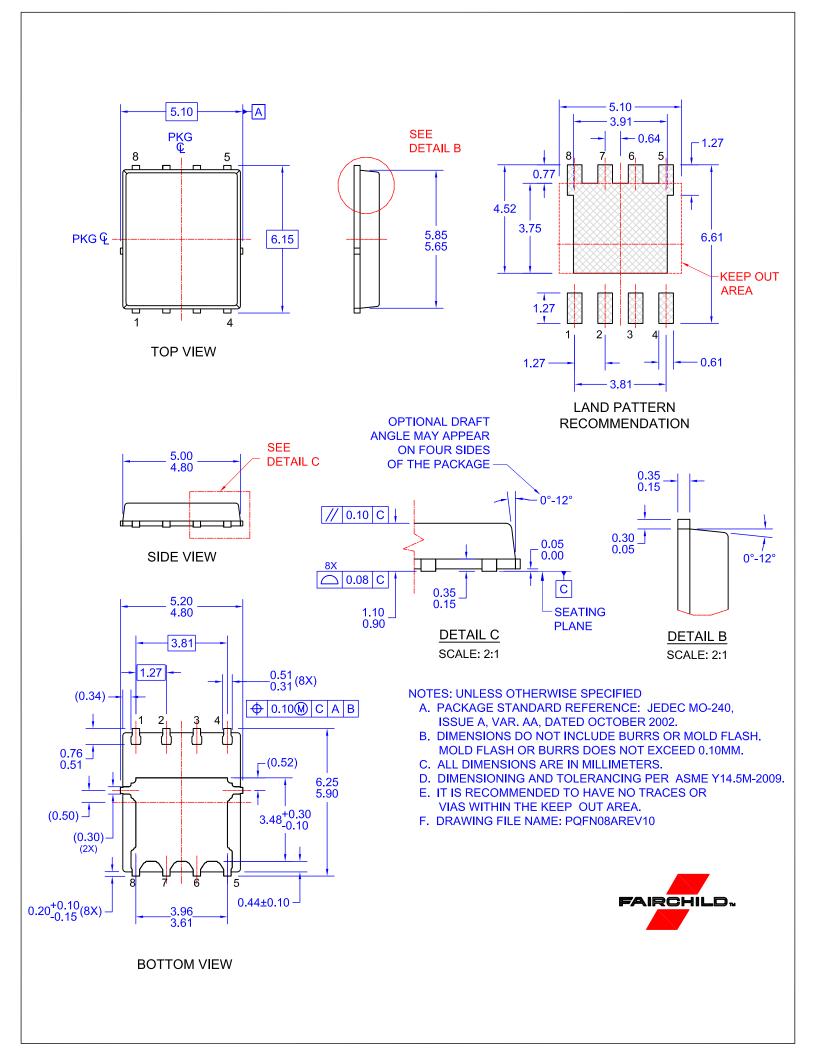


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